MATH 205: Statistical methods

Lecture 30: p-value

Announcement

- Homework 5 is uploaded. Due 12/02.
- Office hour on Friday (11/18) is cancelled.
  Make-up office hours from 1pm-2pm Monday (11/28) and Wednesday (11/30)
- The lecture on Friday (11/18) is also cancelled. A video lecture will be recorded and make available on Canvas.

Chapter 7: Significance of evidence

Hypothesis testing

In a hypothesis-testing problem, there are two contradictory hypotheses under consideration

- The null hypothesis, denoted by H_0, is the claim that is initially assumed to be true
- The alternative hypothesis, denoted by H_a, is the assertion that is contradictory to H_0.
- The null hypothesis will be rejected in favor of the alternative hypothesis only if sample evidence suggests that H_0 is false.
- If the sample does not strongly contradict H_0, we will continue to believe in the probability of the null hypothesis.

Test about a population mean

- Null hypothesis

$$H_0 : \mu = \mu_0$$

- The alternative hypothesis will be either:
  - $H_a : \mu > \mu_0$
  - $H_a : \mu < \mu_0$
  - $H_a : \mu \neq \mu_0$

Statistical "Proof by contradiction"

Ideas:

- Assume that a hypothesis (the null hypothesis) is true
- We ask ourselves, what is the probability that we'll see a dataset as contradictory as (or more contradictory than) the current one?
- That probability is referred to as the p-value (also called **observed significance level**) of the test
- If the p-value is less than a predetermined threshold (called **significant level**, often denoted by α), then we reject the null hypothesis

Note: "contradictory" is a relative concept and is reflected through the alternative hypothesis

z-test

- Given a random sample of size n from a normal distribution with mean μ (unknown) and known population standard deviation σ
- Assume that the data is collected with the measured sample mean $\bar{x}$ and we want to test

$$H_0 : \mu = 15$$
$$H_a : \mu < 15$$

z-test: normal distribution with known σ

- If the null hypothesis $\mu = \mu_0$ is true, then $X_i \sim N(\mu_0, \sigma^2)$
- A sample would be more contradictory to the null hypothesis than the current sample we have if

$$\bar{X} \leq \bar{x} \quad \text{or} \quad \frac{\bar{X} - \mu_0}{\sigma/\sqrt{n}} \leq \frac{\bar{x} - \mu_0}{\sigma/\sqrt{n}}$$

- Thus, the p-value in this case is

$$P\left[Z \leq \frac{\bar{x} - \mu_0}{\sigma/\sqrt{n}}\right] = \Phi\left(\frac{\bar{x} - \mu_0}{\sigma/\sqrt{n}}\right)$$

P-values for z-tests

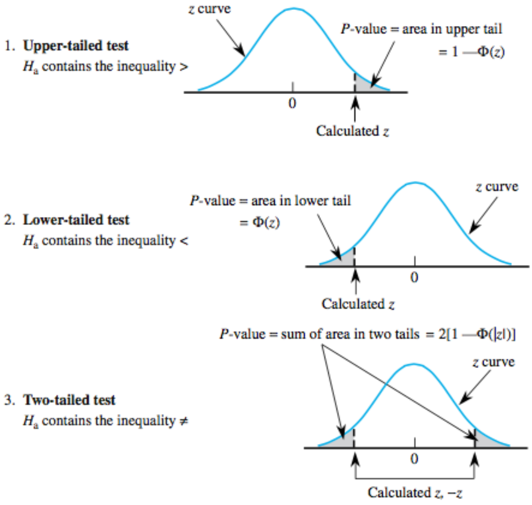

Figure 9.7 Determination of the P-value for a z test

Practice problem

Problem

The target thickness for silicon wafers used in a certain type of integrated circuit is 245 μm. A sample of 50 wafers is obtained and the thickness of each one is determined, resulting in a sample mean thickness of 246.18 μm and a sample standard deviation of 3.60 μm.
At signififcant level $\alpha = 0.01$, does this data suggest that true average wafer thickness is something other than the target value?

$\Phi(z)$

z	.00	.01	.02	.03	.04	.05	.06	.07	.08	.09
0.0	.5000	.5040	.5080	.5120	.5160	.5199	.5239	.5279	.5319	.5359
0.1	.5398	.5438	.5478	.5517	.5557	.5596	.5636	.5675	.5714	.5753
0.2	.5793	.5832	.5871	.5910	.5948	.5987	.6026	.6064	.6103	.6141
0.3	.6179	.6217	.6255	.6293	.6331	.6368	.6406	.6443	.6480	.6517
0.4	.6554	.6591	.6628	.6664	.6700	.6736	.6772	.6808	.6844	.6879
0.5	.6915	.6950	.6985	.7019	.7054	.7088	.7123	.7157	.7190	.7224
0.6	.7257	.7291	.7324	.7357	.7389	.7422	.7454	.7486	.7517	.7549
0.7	.7580	.7611	.7642	.7673	.7704	.7734	.7764	.7794	.7823	.7852
0.8	.7881	.7910	.7939	.7967	.7995	.8023	.8051	.8078	.8106	.8133
0.9	.8159	.8186	.8212	.8238	.8264	.8289	.8315	.8340	.8365	.8389
1.0	.8413	.8438	.8461	.8485	.8508	.8531	.8554	.8577	.8599	.8621
1.1	.8643	.8665	.8686	.8708	.8729	.8749	.8770	.8790	.8810	.8830
1.2	.8849	.8869	.8888	.8907	.8925	.8944	.8962	.8980	.8997	.9015
1.3	.9032	.9049	.9066	.9082	.9099	.9115	.9131	.9147	.9162	.9177
1.4	.9192	.9207	.9222	.9236	.9251	.9265	.9278	.9292	.9306	.9319
1.5	.9332	.9345	.9357	.9370	.9382	.9394	.9406	.9418	.9429	.9441
1.6	.9452	.9463	.9474	.9484	.9495	.9505	.9515	.9525	.9535	.9545
1.7	.9554	.9564	.9573	.9582	.9591	.9599	.9608	.9616	.9625	.9633
1.8	.9641	.9649	.9656	.9664	.9671	.9678	.9686	.9693	.9699	.9706
1.9	.9713	.9719	.9726	.9732	.9738	.9744	.9750	.9756	.9761	.9767
2.0	.9772	.9778	.9783	.9788	.9793	.9798	.9803	.9808	.9812	.9817
2.1	.9821	.9826	.9830	.9834	.9838	.9842	.9846	.9850	.9854	.9857
2.2	.9861	.9864	.9868	.9871	.9875	.9878	.9881	.9884	.9887	.9890
2.3	.9893	.9896	.9898	.9901	.9904	.9906	.9909	.9911	.9913	.9916
2.4	.9918	.9920	.9922	.9925	.9927	.9929	.9931	.9932	.9934	.9936
2.5	.9938	.9940	.9941	.9943	.9945	.9946	.9948	.9949	.9951	.9952
2.6	.9953	.9955	.9956	.9957	.9959	.9960	.9961	.9962	.9963	.9964
2.7	.9965	.9966	.9967	.9968	.9969	.9970	.9971	.9972	.9973	.9974
2.8	.9974	.9975	.9976	.9977	.9977	.9978	.9979	.9979	.9980	.9981
2.9	.9981	.9982	.9982	.9983	.9984	.9984	.9985	.9985	.9986	.9986
3.0	.9987	.9987	.9987	.9988	.9988	.9989	.9989	.9989	.9990	.9990
3.1	.9990	.9991	.9991	.9991	.9992	.9992	.9992	.9992	.9993	.9993
3.2	.9993	.9993	.9994	.9994	.9994	.9994	.9994	.9995	.9995	.9995
3.3	.9995	.9995	.9995	.9996	.9996	.9996	.9996	.9996	.9996	.9997

P-values for z-tests

1. Parameter of interest: μ = true average wafer thickness
2. Null hypothesis: H_0: $\mu = 245$
3. Alternative hypothesis: H_a: $\mu \neq 245$
4. Formula for test statistic value: $z = \dfrac{\bar{x} - 245}{s/\sqrt{n}}$
5. Calculation of test statistic value: $z = \dfrac{246.18 - 245}{3.60/\sqrt{50}} = 2.32$
6. Determination of P-value: Because the test is two-tailed,

$$P\text{-value} = 2[1 - \Phi(2.32)] = .0204$$

7. Conclusion: Using a significance level of .01, H_0 would not be rejected since .0204 > .01. At this significance level, there is insufficient evidence to conclude that true average thickness differs from the target value.

P-values for z-tests

$$P\text{-value:}\quad P = \begin{cases} 1 - \Phi(z) & \text{for an upper-tailed test} \\ \Phi(z) & \text{for a lower-tailed test} \\ 2[1 - \Phi(|z|)] & \text{for a two-tailed test} \end{cases}$$

Practice problem

Problem

The target thickness for silicon wafers used in a certain type of integrated circuit is 245 μm. A sample of 50 wafers is obtained and the thickness of each one is determined, resulting in a sample mean thickness of 246.18 μm and a sample standard deviation of 3.60 μm.

Does this data suggest that true average wafer thickness is larger than the target value? Carry out a test of significance at level .01 and provide the corresponding P-value.

Interpreting P-values

A P-value:

- is not the probability that H_0 is true
- is not the probability of rejecting H_0
- is the probability, calculated assuming that H_0 is true, of obtaining a test statistic value at least as contradictory to the null hypothesis as the value that actually resulted

Problem 1

A company that makes cola drinks states that the mean caffeine content per one 12-ounce bottle of cola is 40 milligrams. You work as a quality control manager and are asked to test this claim. During your tests, you find that a random sample of 30 bottles of cola (12-ounce) has a mean caffeine content of 39.2 milligrams. From a previous study, you know that the standard deviation of the population is $\sigma = 7.5$ milligrams. We assume that the caffeine content is normally distributed.

(a) (20 points) At α= 1% level of significant, can you reject the company's claim? What is the P-value associated with the test?